

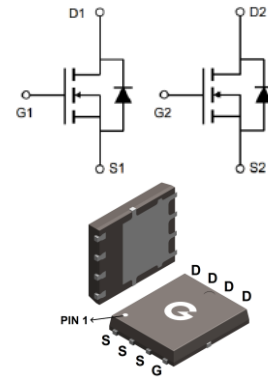
### Features

- Super Low Gate Charge
- Green Device Available
- Excellent CdV/dt Effect Decline
- Advanced High Cell Density Trench Technology

HF

### Mechanical Data

- Case: PDFN5x6-8LC
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208



PDFN5×6-8LC

### Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
GBLN3303-5DL8	PDFN5x6-8LC	5000 pcs / Tape & Reel	GBLN3303

### Maximum Ratings (@ T<sub>A</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	30	V
Gate-to-Source Voltage	V <sub>GSS</sub>	±20	V
Continuous Drain Current (T <sub>C</sub> = 25°C)	I <sub>D</sub>	20	A
Continuous Drain Current (T <sub>A</sub> = 25°C) *1		6.4	A
Continuous Drain Current (T <sub>A</sub> = 100°C) *1		4	A
Pulsed Drain Current (t <sub>p</sub> = 10μs, T <sub>A</sub> = 25°C)	I <sub>DM</sub>	60	A
Single Pulse Avalanche Energy *3	E <sub>AS</sub>	40	mJ
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	21	W
Power Dissipation (T <sub>A</sub> = 25°C) *1		2	W
Operating Junction Temperature Range	T <sub>J</sub>	-55 ~ +150	°C
Storage Temperature Range	T <sub>STG</sub>	-55 ~ +150	°C

### Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	R <sub>θJC</sub>	-	-	6	°C/W
Thermal Resistance Junction-to-Air *1	R <sub>θJA</sub>	-	-	62	°C/W

### Electrical Characteristics-TR1 (@ T<sub>A</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
V <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	-	-	1	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA
<b>On Characteristics</b>						
R <sub>DS(ON)</sub>	Drain-Source On-resistance <sup>*2</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 6.3A	-	18	30	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 4.8A	-	25	45	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1	1.6	2.5	V
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 0V, f = 1MHz	-	8.4	-	Ω
<b>Dynamic Characteristics</b>						
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0V V <sub>DS</sub> = 15V f = 1.0MHz	-	492	-	pF
C <sub>OSS</sub>	Output Capacitance		-	64	-	
C <sub>RSS</sub>	Reverse Transfer Capacitance		-	59	-	
<b>Switching Characteristics</b>						
t <sub>d(ON)</sub>	Turn-on Delay Time <sup>*4</sup>	V <sub>GS</sub> = 10V V <sub>DD</sub> = 15V R <sub>L</sub> = 2.6Ω R <sub>G</sub> = 3Ω	-	4.5	-	ns
t <sub>r</sub>	Turn-on Rise Time <sup>*4</sup>		-	2.4	-	
t <sub>d(OFF)</sub>	Turn-Off Delay Time <sup>*4</sup>		-	14.8	-	
t <sub>f</sub>	Turn-Off Fall Time <sup>*4</sup>		-	2.5	-	
Q <sub>G</sub>	Total Gate-Charge	V <sub>DD</sub> = 15V V <sub>GS</sub> = 10V I <sub>D</sub> = 5.8A	-	14.6	-	nC
Q <sub>GS</sub>	Gate to Source Charge		-	2.4	-	
Q <sub>GD</sub>	Gate to Drain (Miller) Charge		-	2.9	-	
<b>Source-Drain Diode Characteristics</b>						
V <sub>SD</sub>	Diode Forward Voltage <sup>*2</sup>	I <sub>SD</sub> = 1A, V <sub>GS</sub> = 0V	-	0.8	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 5A, V <sub>GS</sub> = 0V d <sub>I</sub> F/d <sub>t</sub> = 100A/μs	-	75	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	36	-	nC

Notes:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper
2. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%
3. The E<sub>AS</sub> data shows Max. rating. The test condition is V<sub>DD</sub> = 25V, V<sub>GS</sub> = 10V, L = 10mH
4. Guaranteed by design, not subject to production

Ratings and Characteristics Curves (@  $T_A = 25^\circ\text{C}$  unless otherwise specified)

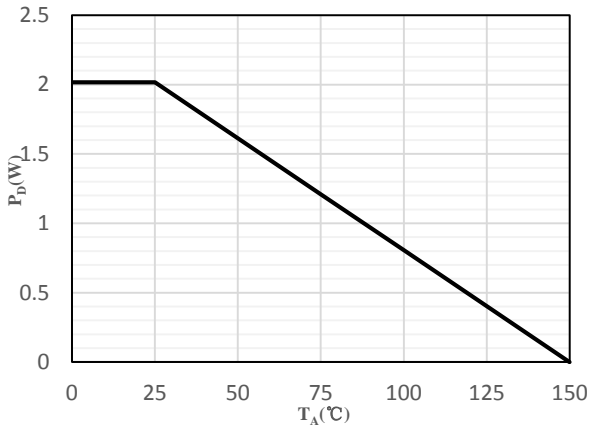


Fig 1 Power Dissipation

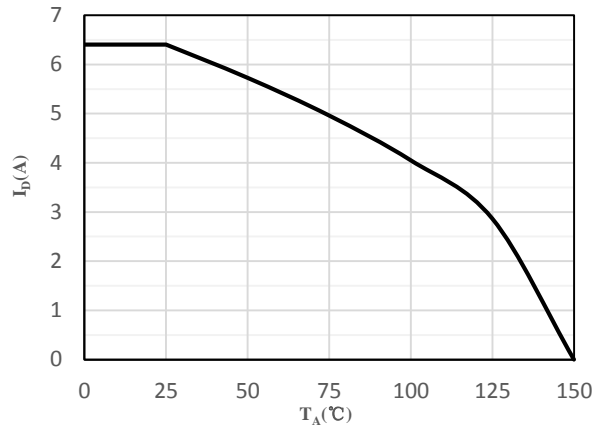


Fig 2 Drain Current

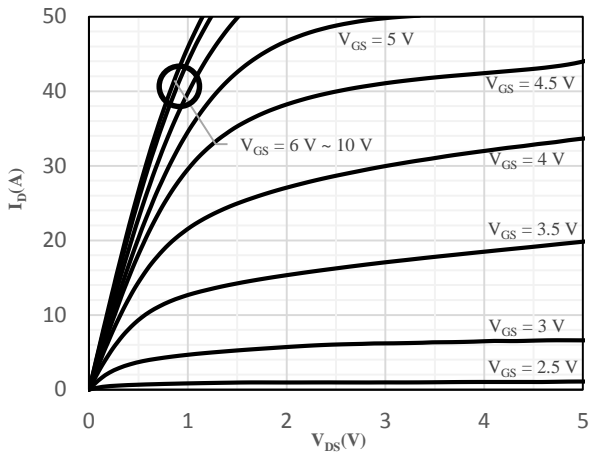


Fig 3 Typical Output Characteristics

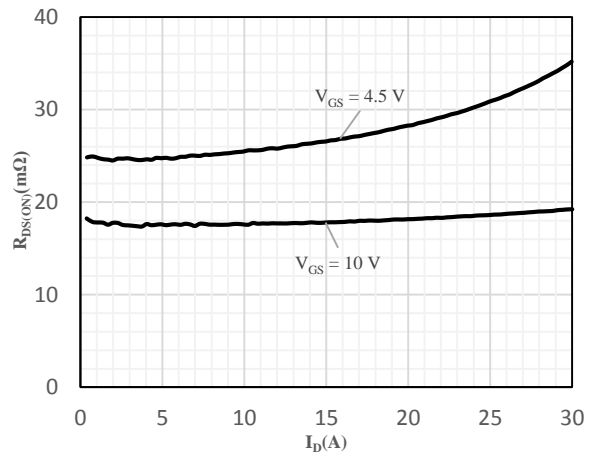


Fig 4 On-Resistance vs. Drain Current and Gate Voltage

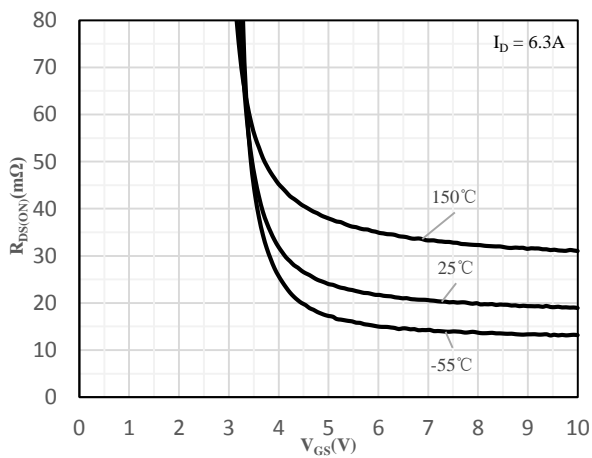


Fig 5 On-Resistance vs. Gate-Source Voltage

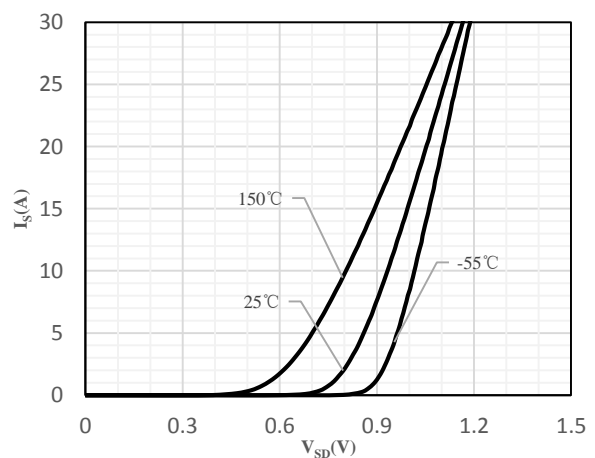


Fig 6 Body-Diode Characteristics

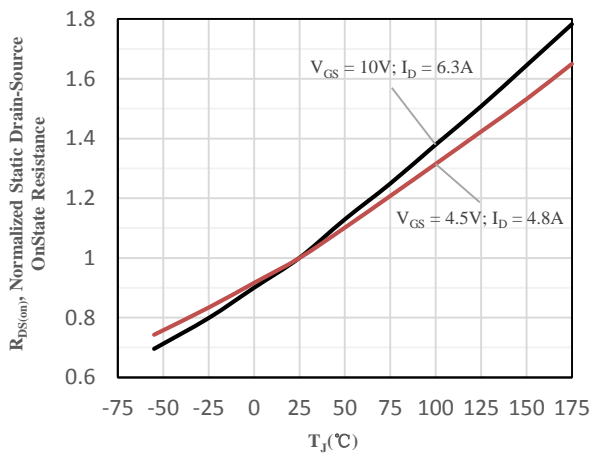


Fig 7 Normalized On-Resistance vs. Junction Temperature

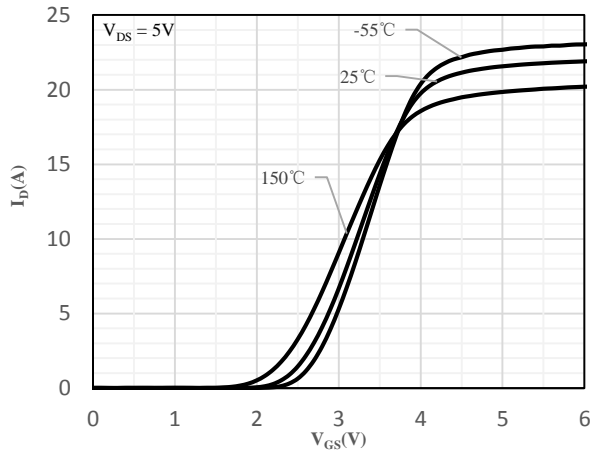


Fig 8 Transfer Characteristics

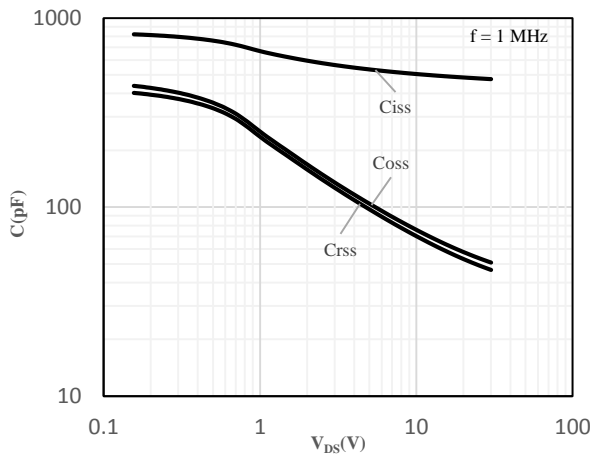


Fig 9 Capacitance Characteristics

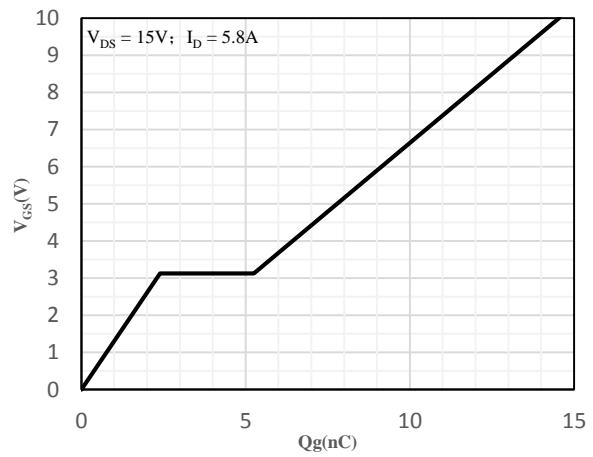


Fig 10 Gate-Charge Characteristics

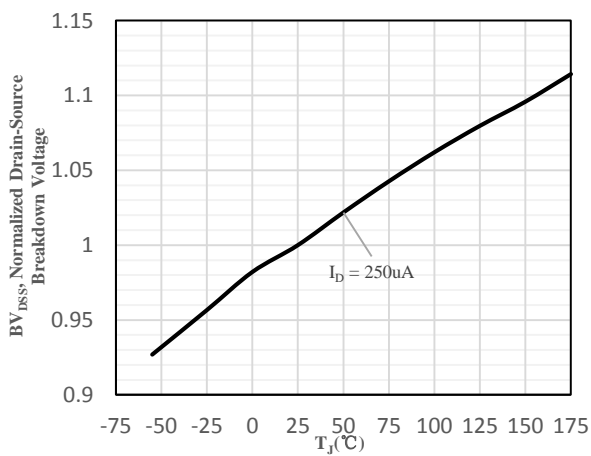


Fig 11 Normalized Breakdown Voltage vs. Junction Temperature

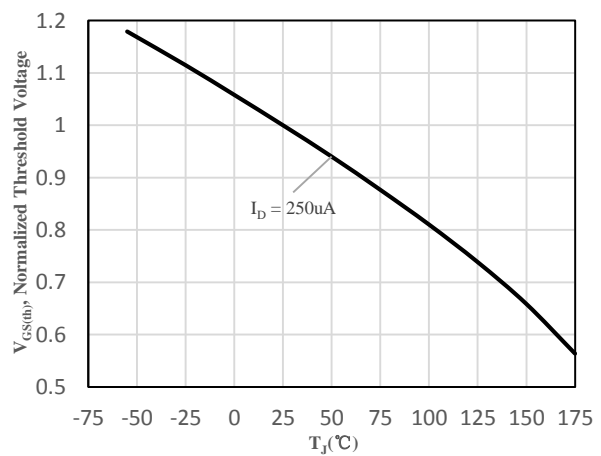


Fig 12 Normalized  $V_{GS(th)}$  vs. Junction Temperature

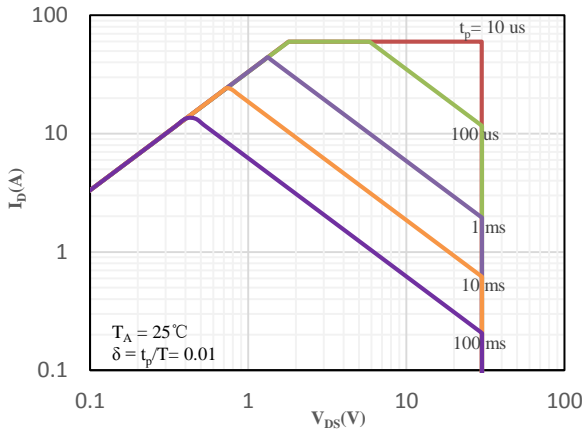


Fig 13 Safe Operation Area

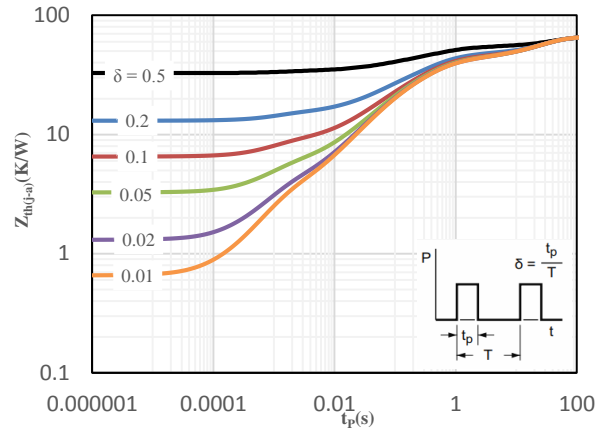
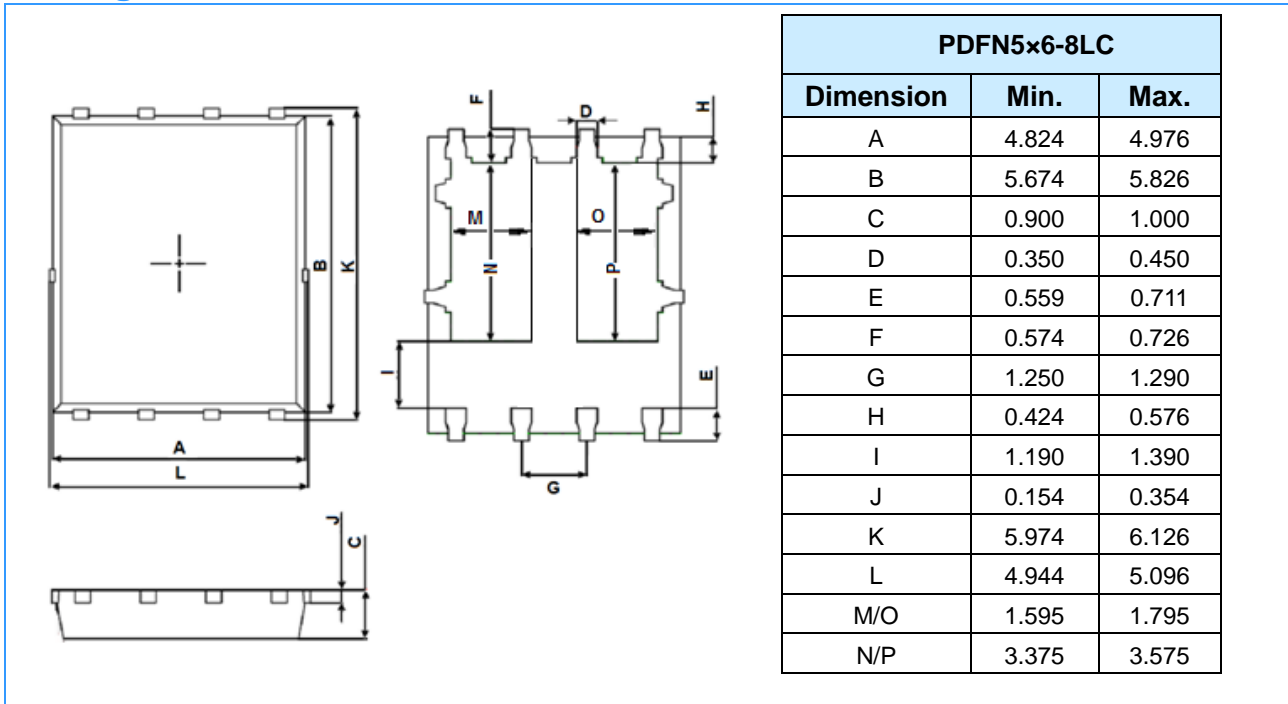
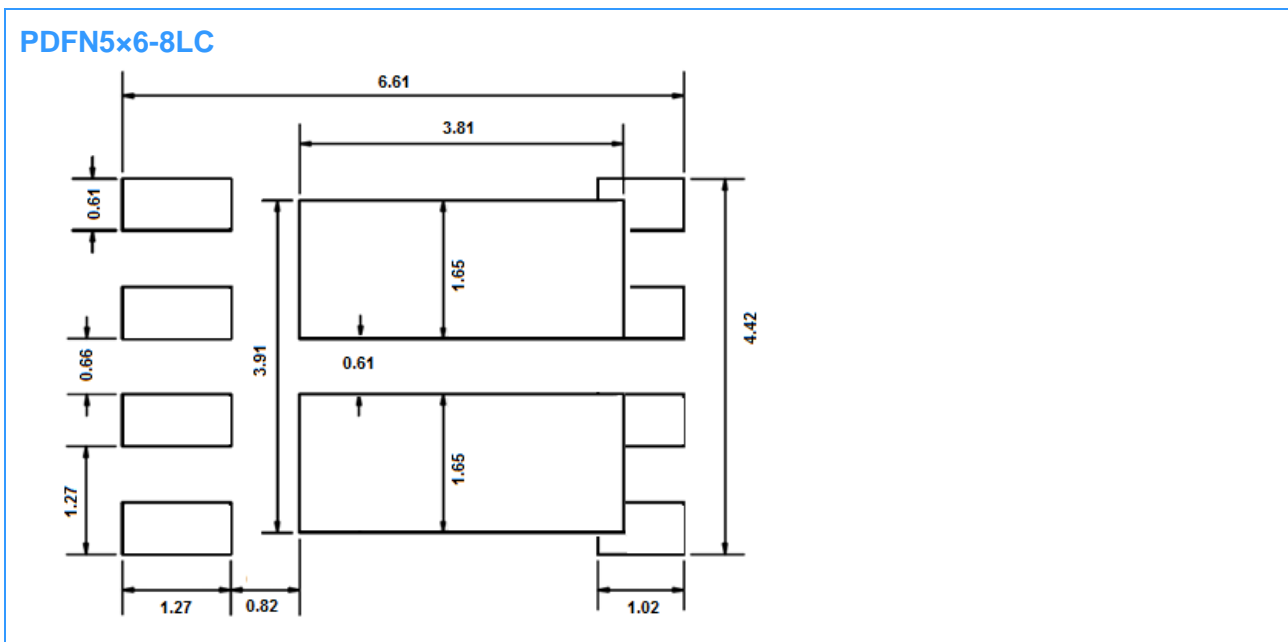


Fig 14 Maximum transient thermal impedance

### Package Outline Dimensions (Unit: mm)



### Mounting Pad Layout (Unit: mm)



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